Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/636,105	YIN ET AL.
Examiner	Art Unit
Donahai D. Nauvan	2720

SEARCHED					
Class	Subclass	Date	Examiner		
29	831, 832, 834, 838- 841	3/23/2006	DN		
174	260, 261	\	1		
228	173.2				
	180.21				
257	752, 753				
	783				
	788-793				
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438	108, 125				
	156, 692	V	V		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East Search Updated (see attached)	3/23/2006	<i>®</i> ∼